

<b>Notice of References Cited</b>	Application/Control No. 10/565,949	Applicant(s)/Patent Under Reexamination WEISS ET AL.	
	Examiner Hai H. Huynh	Art Unit 3747	Page 1 of 1

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*	C	US-2004/0123834 A1	07-2004	Wagner et al.	123/295
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**NON-PATENT DOCUMENTS**

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